

Final Product/Process Change Notification Document #: FPCN21060ZA

Issue Date: 22 October 2015

Title of Change:	Pd-coated Cu wire qualification on SOT23 transistor and Bias Resistor Transistor at ON Semiconductor, Leshan, China facility				
Proposed first ship date:	22 October 2016 or earlier upon customer approval				
Contact information:	Contact your local ON Semiconductor Sales Office or andy.tao@onsemi.com >				
Samples:	Contact your local ON Semiconductor Sales Office or andy.tao@onsemi.com >				
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office or < <u>S1016z@onsemi.com</u> >				
Type of notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 12 month prior to implementation of the change. ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact <pcn.support@onsemi.com>.</pcn.support@onsemi.com>				
Change Part Identification:	At the expiration of this FPCN devices will be assembled with Pd-coated Cu Wire at ON Semiconductor's existing Leshan facility. Products assembled with Pd-coated Cu Wire from the ON Semiconductor facility will have a Finish Goods Date Code of WW39, 2016 or greater				
Change category:	ry:				
Change Sub-Category(s): Manufacturing Site Change/ Manufacturing Process Chan					
Sites Affected: All site(s) not app	olicable Son Semiconductor site(s): ON Leshan, China External Foundry/Subcon site(s)				
Description and Purpose:					
ON Semiconductor is notifying customer of its use of Pd-coated Cu wire for their impacted devices at ON Semiconductor's Leshan, China facility. Discrete products built with bipolar transistor are represented by this Process Change Notice.					
At the expiration of this PCN, these devices will be built with Pd-coated Cu wire at the same site. Datasheet specifications and product electrical performance remain unchanged. Full electrical characterization over temperature has been performed.					
Reliability Data Summary: SOT23					

BCX19LT1G

Test	Specification	Condition	Interval	Results
HTRB	JESD22-A108	Ta= 150°C, 80% max rated V	1008 hrs	0/252
HTSL	JESD22-A103	Ta= 150C	1008 hrs	0/252
IOL	MIL-STD-750	Ta=+25°C, delta Tj=100°C		
	(M1037)	On/off = 2 min	15000 cyc	0/252
	AEC-Q101			
TC	JESD22-A104	Ta= - 65°C to +150°C	1000 сус	0/252
HAST	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs	0/252
AC	JESD22-A102	121°C, 100% RH, ~15psig, unbiased	96 hrs	0/252
RSH	JESD22- B106	Ta = 265C, 10 sec		0/90

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SOT23 MMBT2907ALT1G

Test	Specification	Condition	Interval	Results
HTRB	JESD22-A108	Ta= 150°C, 80% max rated V	1008 hrs	0/252
HTSL	JESD22-A103	Ta= 150C	1008 hrs	0/252
IOL	MIL-STD-750	Ta=+25°C, delta Tj=100°C		
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AC	JESD22-A102	121°C, 100% RH, ~15psig, unbiased	96 hrs	0/252
RSH	JESD22- B106	Ta = 265C, 10 sec		0/90

Electrical Characteristic Summary:

Three temperature characterization and ESD performance meet datasheet specification. Detail of Electrical characterization result is available upon request.

List of Affected Standard Parts:

Part Number	Qualification Vehicle	
NSVMMUN2235LT1G	BCX19LT1G	
NSVMMUN2233LT3G	BCX19LT1G	
NSVMMUN2135LT1G	MMBT2907ALT1G	
NSVMMBT5401LT3G	MMBT2907ALT1G	
NSVMMBT5088LT3G	BCX19LT1G	
NSVMMBT5087LT1G	MMBT2907ALT1G	
NSVBC857BLT3G	MMBT2907ALT1G	
NSVBC850CLT1G	BCX19LT1G	
NSVBC850BLT1G	BCX19LT1G	
NSVBC847BLT3G	BCX19LT1G	
NSVBC817-16LT1G	BCX19LT1G	
NSVBCX17LT1G	MMBT2907ALT1G	
NSVBCW68GLT1G	MMBT2907ALT1G	
NSVBCW32LT1G	BCX19LT1G	
NSVMMUN2230LT1G	BCX19LT1G	
NSVMMUN2113LT3G	MMBT2907ALT1G	
NSVMMUN2114LT3G	MMBT2907ALT1G	
NSVMMBT5087LT3G	MMBT2907ALT1G	
NSVMMBTA05LT1G	BCX19LT1G	

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